Device Modeling Report

COMPONENTS: BIPOLAR JUNCTION TRANSISTOR

PART NUMBER: 2SC5172 MANUFACTURER: TOSHIBA

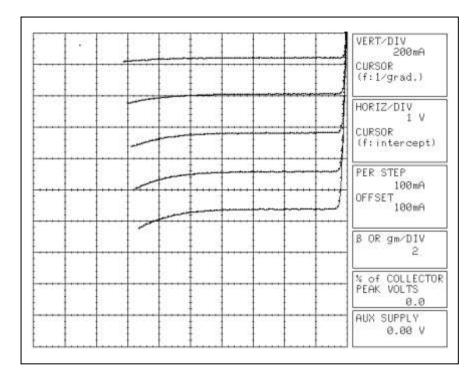


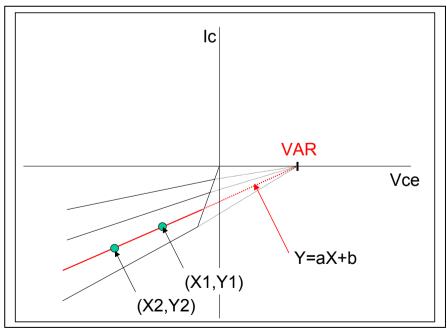
Bee Technologies Inc.

PSpice				
model	Model description			
parameter				
IS	Saturation Current			
BF	Ideal Maximum Forward Beta			
NF	Forward Current Emission Coefficient			
VAF	Forward Early Voltage			
IKF	Forward Beta Roll-off Knee Current			
ISE	Non-ideal Base-Emitter Diode Saturation Current			
NE	Non-ideal Base-Emitter Diode Emission Coefficient			
BR	Ideal Maximum Reverse Beta			
NR	Reverse Emission Coefficient			
VAR	Reverse Early Voltage			
IKR	Reverse Beta Roll-off Knee Current			
ISC	Non-ideal Base-Collector Diode Saturation Current			
NC	Non-ideal Base-Collector Diode Emission Coefficient			
NK	Forward Beta Roll-off Slope Exponent			
RE	Emitter Resistance			
RB	Base Resistance			
RC	Series Collector Resistance			
CJE	Zero-bias Emitter-Base Junction Capacitance			
VJE	Emitter-Base Junction Potential			
MJE	Emitter-Base Junction Grading Coefficient			
CJC	Zero-bias Collector-Base Junction Capacitance			
VJC	Collector-base Junction Potential			
MJC	Collector-base Junction Grading Coefficient			
FC	Coefficient for Onset of Forward-bias Depletion			
	Capacitance			
TF	Forward Transit Time			
XTF	Coefficient for TF Dependency on Vce			
VTF	Voltage for TF Dependency on Vce			
ITF	Current for TF Dependency on Ic			
PTF	Excess Phase at f=1/2pi*TF			
TR	Reverse Transit Time			
EG	Activation Energy			
XTB	Forward Beta Temperature Coefficient			
XTI	Temperature Coefficient for IS			

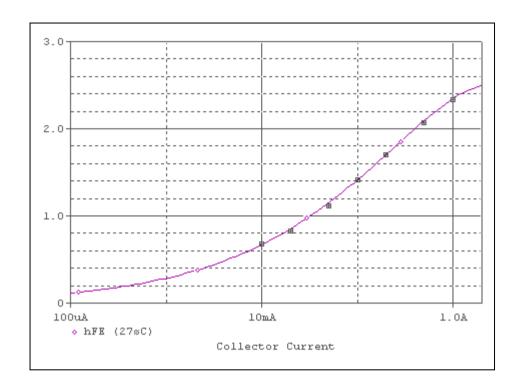
Reverse

Reverse Early Voltage Characteristic



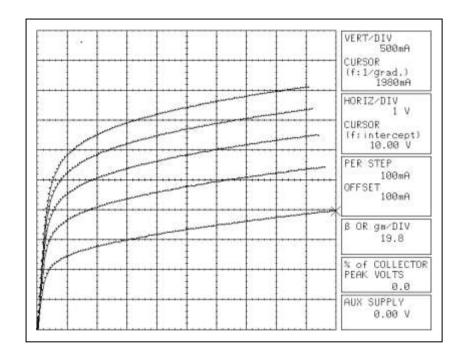


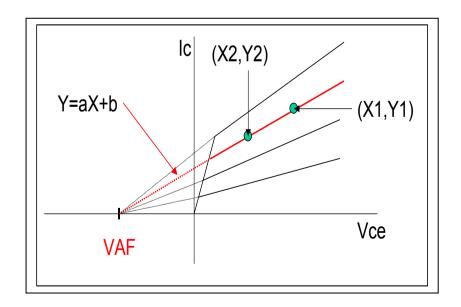
Reverse DC Beta Characteristic (le vs. hfe)



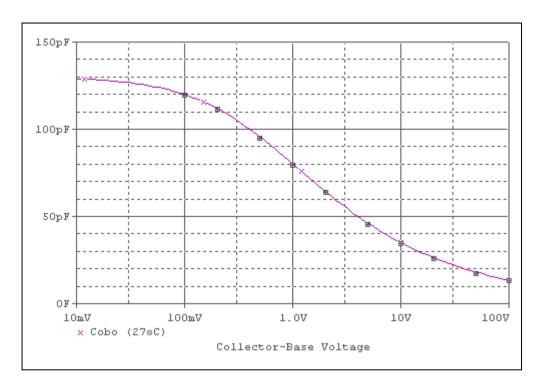
Forward

Forward Early Voltage Characteristic

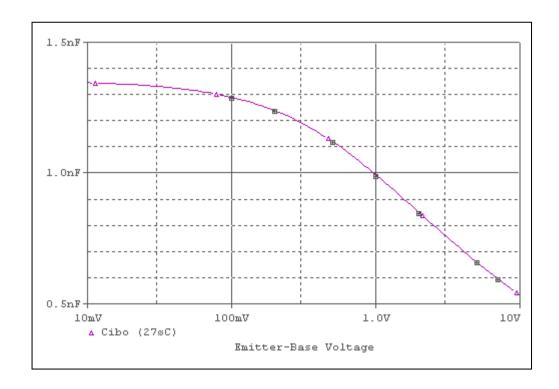




C-B Capacitance Characteristic

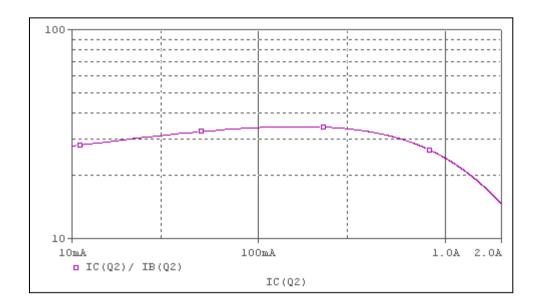


E-B Capacitance Characteristic

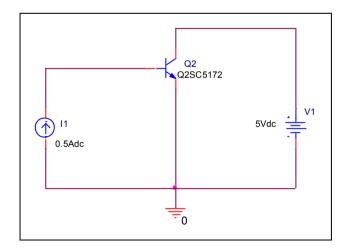


BJT Ic-hfe Characteristics

Circuit simulation result

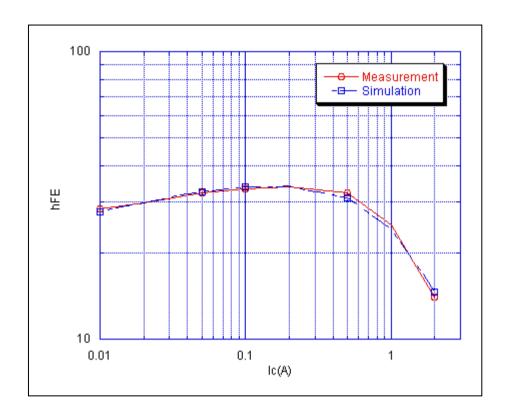


Evaluation circuit



Comparison Graph

Circuit simulation result

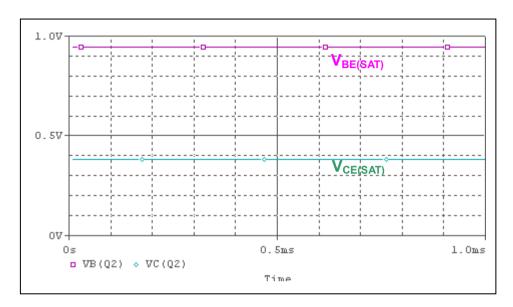


Simulation result

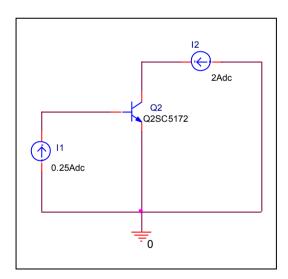
Io/A)	hFE	0/ Exxox	
Ic(A)	Measurement	Simulation	%Error
0.01	28.33	27.69	- 2.259
0.02	29.851	29.888	0.123
0.05	32.258	32.525	0.827
0.1	33.333	33.983	1.950
0.2	33.898	34.273	1.106
0.5	32.258	31.009	- 3.871
1	25	24.258	- 2.968
2	14	14.593	4.235

BJT Vce(sat) voltage & Vbe(sat) voltage Characteristics

Circuit simulation result



Evaluation circuit



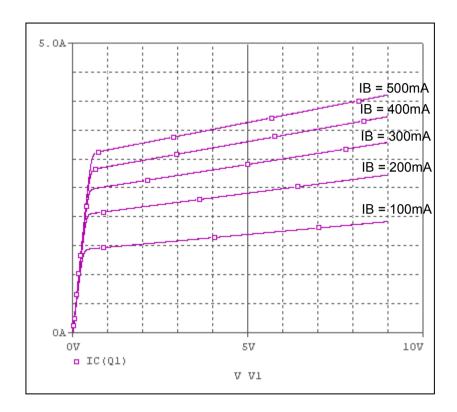
Simulation result

Test condition: IC/IB = 8, IC=2A

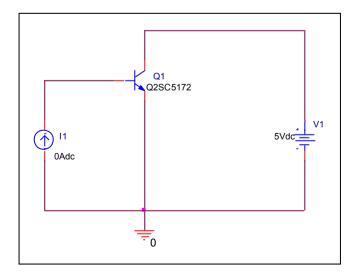
Vce(sat)(V)			V	be(sat)(V)	
Measurement	Simulation	Error(%)	Measurement	Simulation	Error(%)
0.390	0.381	- 2.308	0.939	0.943	0.426

Output Characteristics

Circuit simulation result



Evaluation circuit



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Output Characteristics

Reference

